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ATTY. DOCKET NO.

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4105-19

10/615,415

APPLICANT

ONOE et al.

FILING DATE

TC/A.U.

July 9, 2003

2627

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
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TT	62th Japan Society of Applied Physics Lecture Meeting (2001.9 Aichi Institute of Technology) 12p-ZR-2.

\*Examiner

/Thang Tran/

Date Considered

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DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS		YES	NO

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